

<b>Notice of References Cited</b>	Application/Control No. 10/649,399		Applicant(s)/Patent Under Reexamination DOLITZKY ET AL.	
	Examiner Mark L. Berch		Art Unit 1624	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2008/0154038	06-2008	Chiodini et al.	544/277
*	B	US-5,246,937 A	09-1993	Harnden et al.	514/263.4
*	C	US-7,473,780	01-2009	Eisen-Nevo et al.	544/277
*	D	US-6,388,074 B2	05-2002	Geen et al.	544/276
*	E	US-5,684,153 A	11-1997	Geen et al.	544/276
*	F	US-7,456,282	11-2008	Lee et al.	544/277
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	Wang, et al., Jilin Daxue Ziran Kexue Xuebao (2000), (1), 95-98			
	V	Translation of Wang, et al., Jilin Daxue Ziran Kexue Xuebao (2000), (1), 95-98			
	W	Geen et al., Tetrahedron letters 33, 4609 (1992)			
	X				

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.